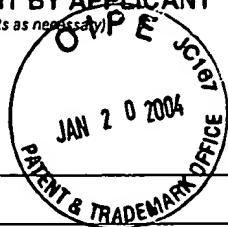


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	Application Number	09/069668
	Filing Date	April 29, 1998
	First Named Inventor	Ahn, Kie
	Group Art Unit	2823
	Examiner Name	Coleman, W.
Sheet 1 of 1	Attorney Docket No: 303.466US1	



US PATENT DOCUMENTS						
Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS						
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Examiner Initials *	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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EXAMINER

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Title of Invention	BIPOLAR TRANSISTORS WITH LOW-RESISTANCE EMITTER CONTACTS																																																																														
<p>Application Number: 09/069668 </p> <p>Confirmation Number: 3628</p> <p>First Named Applicant: Kie Ahn</p> <p>Attorney Docket Number: 303.466US1</p> <p>Art Unit: 2823</p> <p>Examiner: W. Coleman</p> <p>Search string: (3932226 or 4169000 or 4442449 or 4670297 or 4855252 or 4857481 or 4959705 or 5040049 or 5148260 or 5158986 or 5187560 or 5241193 or 5268315 or 5308440 or 5334356 or 5391911 or 5454928 or 5458702 or 5501645 or 5516724 or 5516745 or 5539227 or 5563448 or 5593921 or 5705425 or 5710454 or 5753967 or 5757072 or 5796151 or 5796166 or 5798544 or 5798559 or 5847439 or 5861340 or 5891797 or 5920121 or 5925918 or 5925933 or 5930596 or 5930668 or 5942799 or 5960313 or 5989718 or 6025261 or 6080646 or 6150252 or 6157082 or 6180509 or 6211562 or 6245663 or 6265602 or 6271551).pn.</p> <p>US Patent Documents</p> <p>Note: Applicant is not required to submit a paper copy of cited US Patent Documents</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Patent No.</th><th>Date</th><th>Patentee</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td></td><td>1</td><td>3932226</td><td>1976-01-13</td><td>Klatskin, J. B., et al.</td><td></td><td>204</td><td>16</td></tr><tr><td></td><td>2</td><td>4169000</td><td>1979-09-25</td><td>Riseman, J.</td><td></td><td>148</td><td>187</td></tr><tr><td></td><td>3</td><td>4442449</td><td>1984-04-10</td><td>Lehrer, W. I., et al.</td><td></td><td>357</td><td>67</td></tr><tr><td></td><td>4</td><td>4670297</td><td>1987-06-02</td><td>Lee, K., et al.</td><td></td><td>427</td><td>91</td></tr><tr><td></td><td>5</td><td>4855252</td><td>1989-08-08</td><td>Peterman, Steven</td><td></td><td>437</td><td>189</td></tr><tr><td></td><td>6</td><td>4857481</td><td>1989-08-15</td><td>Tam, G., et al.</td><td></td><td>437</td><td>182</td></tr><tr><td></td><td>7</td><td>4959705</td><td>1990-09-25</td><td>Lemnios,</td><td></td><td>257</td><td>522</td></tr><tr><td></td><td>8</td><td>5040049</td><td>1991-08-13</td><td>Raaijmakers, I. J.</td><td></td><td>357</td><td>71</td></tr></tbody></table>								init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass		1	3932226	1976-01-13	Klatskin, J. B., et al.		204	16		2	4169000	1979-09-25	Riseman, J.		148	187		3	4442449	1984-04-10	Lehrer, W. I., et al.		357	67		4	4670297	1987-06-02	Lee, K., et al.		427	91		5	4855252	1989-08-08	Peterman, Steven		437	189		6	4857481	1989-08-15	Tam, G., et al.		437	182		7	4959705	1990-09-25	Lemnios,		257	522		8	5040049	1991-08-13	Raaijmakers, I. J.		357	71
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Signature

Examiner Name	Date
<i>Michelle D. Al</i>	<i>3/22/04</i>